

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/777,576	FURUKAWA ET AL.	
Examiner	Art Unit	
Ori Nadav	2811	

SEARCHED					
Class	Subclass	Date	Examiner		
Updated	search	3/17/2007	O.N.		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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